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Minimal material, maximum coverage: Silicon Tracking System for high-occupancy conditions

Silicon strip sensors have long been a reliable technology for particle detection. Here, we push the limits of silicon tracking detectors by targeting an unprecedentedly low material budget of 2%–7% X_0 in an 8-layer 4m² detector designed for high-occupancy environments (≤ 10 MHz/cm²).

To achieve this, we employ **Double-Sided Double Metal (DSDM) silicon microstrip sensors**, coupled with readout electronics capable of precise **timing and energy measurements**. These 300 μm thick sensors, featuring 2×1024 channels with a **58 μm pitch**, are connected via ultra-lightweight aluminium-polyimide microcables for signal transmission and integrated with a custom **SMX readout ASIC**, operating in **free-streaming mode**. This system enables the simultaneous measurement of **time ($\Delta t \approx 5$ ns)** and **charge deposition (0.1–100 fC)**, significantly enhancing the detector's capacity for high-precision track reconstruction in high-occupancy and harsh radiation field environments.

The primary application of this technology is the **Silicon Tracking System (STS) for the CBM experiment**, with additional potential in projects like the **J-PARC E16 experiment** and future uses in medical physics, such as advanced imaging telescopes. In this contribution, we present the current status of CBM STS construction, with almost one-third of the modules produced and tested. We also discuss immediate applications and explore promising **prospects in both scientific and medical fields**.

Primary experiment

CBM

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Track Classification: Semiconductor Detectors